General Feature

- Support DDR, DDR2, DDR3 SDRAM & GDDR4 SDRAM
- Variable frequency up to 900MHz (1.8Gbps)
- Support 256DUTs parallel test.
- 1024 channels of device power supply (DPS)
- Built in Fail Memory and Shmoo functions for analysis
- Graphical and text style logging.

Specification

• Memory Types Supported	DDR1, DDR2, DDR3 SDRAM & GDDR4 SDRAM
• Test Frequency	900MHz (1.8Gbps)
• Parallel Test	256DUTs/station
• ALPG	Real Time Algorithmic Pattern Generator
• Test Pattern	Programmable by Unitest pattern language
• Analysis Tool	Fail Memory, Shmoo Plot
• Automated System	Vertical Memory Handler
• Handler Interface	GPIB
• System Software	LINUX based OS Platform



New Technology Tester Leader

UniTest

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Uni Test

Optimum Test Solution in Mass Production For High Speed Memory Device



UNI 5200

The system is capable of reading even relatively unstable data of a high bandwidth by improved Source Synchronous Channel Scheme. Furthermore, thru the Linux based Operation Programs and the easy solution for developing Test Program by C/C++ language, the diverse and complex demands of user are easily and effectively accommodated.

The UNI5200 has capability to test up to 256 devices simultaneously and it is possible to interface with various handlers.

In addition, the ALPG supports up to 4 ways Interleave mode for High-speed operation and offers an easy way to make a memory pattern program.

For testing next generation devices, the data rate of 900Mhz(1.8Gpbs) can be upgraded to 1.2Ghz(2.4Gbps) simply by replacing test speed related boards.